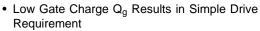


N-Channel 650V (D-S) Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	650			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V 5			
Q _g (Max.) (nC)	11			
Q _{gs} (nC)	2.3			
Q _{gd} (nC)	5.2			
Configuration	Single			

FEATURES

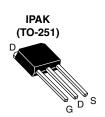


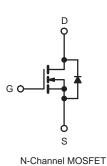


• Improved Gate, Avalanche and Dynamic dV/dt Ruggedness



- Fully Characterized Capacitance and Avalanche Voltage and Current
- Compliant to RoHS directive 2002/95/EC





ABSOLUTE MAXIMUM RATINGS T _C = 25 °C, unless otherwise noted						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	650	V	
Gate-Source Voltage			V_{GS}	± 30	7 v	
Continuous Drain Currente	V _{GS} at 10 V	T _C = 25 °C		2.0		
Continuous Drain Current	V _{GS} at 10 V	T _C = 100 °C	I _D	1.28	Α	
Pulsed Drain Current ^a			I _{DM}	8		
Linear Derating Factor				0.48	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	165	mJ	
Repetitive Avalanche Current ^a			I _{AR}	2	Α	
Repetitive Avalanche Energy ^a			E_{AR}	6	mJ	
Maximum Power Dissipation $T_C = 25 ^{\circ}C$			P_{D}	45	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.8	V/ns	
Operating Junction and Storage Temperature Range			T_J,T_stg	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature) ^d	for 10 s			300]	
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
Woulding Forque				1.1	N⋅m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T_J = 25 °C, L = 24 mH, R_G = 25 Ω , I_{AS} = 3.2 A (see fig. 12).
- c. $I_{SD} \le 3.2$ A, $dI/dt \le 90$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.
- e. Drain current limited by maximum junction temperature.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	65	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	=	2.1	C/VV	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V_{DS}	V _{GS} :	= 0 V, I _D = 250 μA	650	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I _D = 1 mA ^d	-	670	-	mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	,	$V_{GS} = \pm 30 \text{ V}$	ı	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		= 650 V, V _{GS} = 0 V V, V _{GS} = 0 V, T _J = 125 °C	-	-	25 250	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 1 A b	-	4.0	5.0	Ω
Forward Transconductance	9 _{fs}	-	= 50 V, I _D = 1 A	3.9	-	-	S
Dynamic		1					
Input Capacitance	C _{iss}		$V_{GS} = 0 V$,	-	417	-	
Output Capacitance	C _{oss}		$V_{DS} = 25 \text{ V},$	-	45	-	
Reverse Transfer Capacitance	C _{rss}	f = 1	.0 MHz, see fig. 5	-	5	-	
Outrut Consider	•		V _{DS} = 1.0 V, f = 1.0 MHz	-	912	-	pF
Output Capacitance	Coss	$V_{GS} = 0 V$ $V_{DS} = 520 V, f = 10 V$	V _{DS} = 520 V, f = 1.0 MHz	-	26		
Effective Output Capacitance	Coss eff.		V _{DS} = 0 V to 520 V ^c		42	-	
Total Gate Charge	Q_g				-	11	
Gate-Source Charge	Q_{gs}	V _{GS} = 10 V			-	2.3	nC
Gate-Drain Charge	Q _{gd}	see fig. 6 and 13 ^b		-	-	5.2	
Turn-On Delay Time	t _{d(on)}			-	14	-	
Rise Time	t _r		$V_{DD} = 325 \text{ V}, I_D = 1.2 \text{A}$ $R_G = 9.1 \Omega, R_D = 62 \Omega,$ see fig. 10 ^b		20	-	1
Turn-Off Delay Time	t _{d(off)}	$R_{G} =$			34	-	ns -
Fall Time	t _f	j -		-	18	-	
Drain-Source Body Diode Characteristic	s	•					
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	2	A
Pulsed Diode Forward Current ^a	I _{SM}			ı	-	8	A
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 3.2 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$		-	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 3.2 A, dI/dt = 100 A/µs ^b		ı	180	230	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	2.1	3.2	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)				L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 µs; duty cycle \leq 2 %.
- c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .
- d. t = 60 s, f = 60 Hz.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

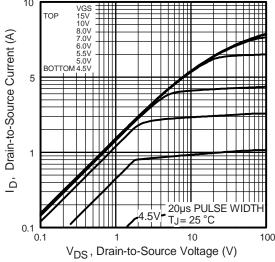


Fig. 1 - Typical Output Characteristics

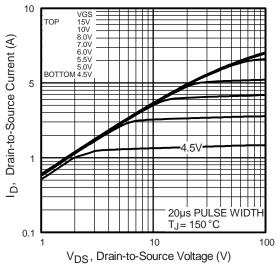


Fig. 2 - Typical Output Characteristics

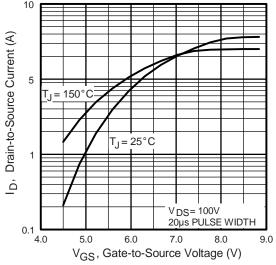


Fig. 3 - Typical Transfer Characteristics

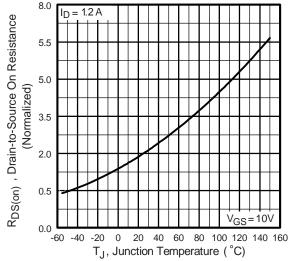


Fig. 4 - Normalized On-Resistance vs. Temperature



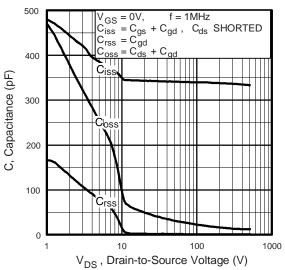


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

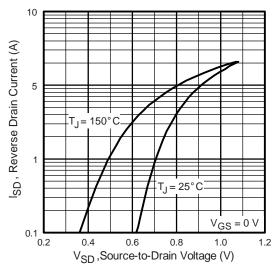


Fig. 7 - Typical Source-Drain Diode Forward Voltage

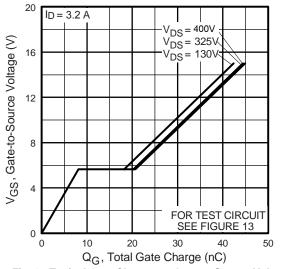


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

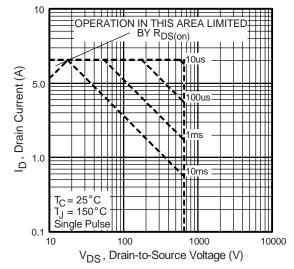


Fig. 8 - Maximum Safe Operating Area



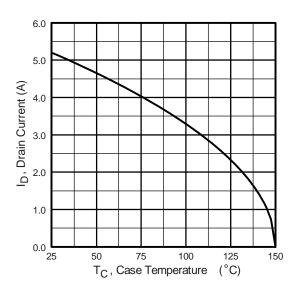


Fig. 9 - Maximum Drain Current vs. Case Temperature

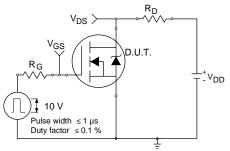


Fig. 10a - Switching Time Test Circuit

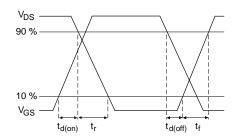


Fig. 10b - Switching Time Waveforms

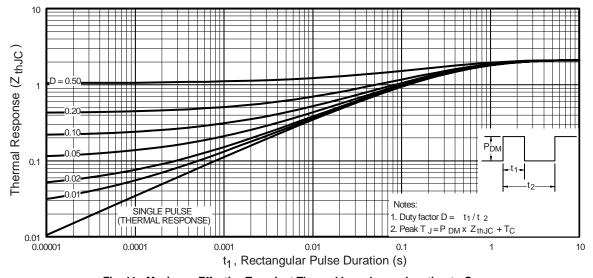


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

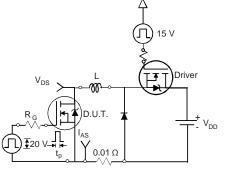


Fig. 12a - Unclamped Inductive Test Circuit

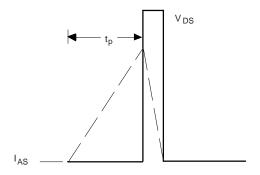


Fig. 12b - Unclamped Inductive Waveforms



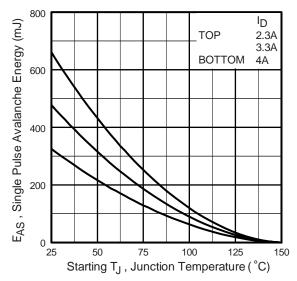


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

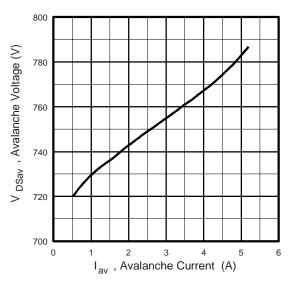


Fig. 12d - Typical Drain-to Source Voltage vs. Avalanche Current

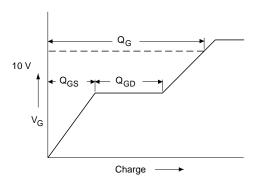


Fig. 13a - Basic Gate Charge Waveform

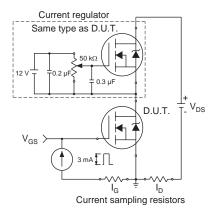
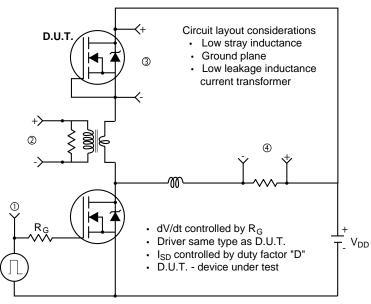
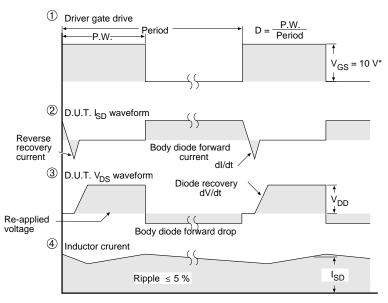


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



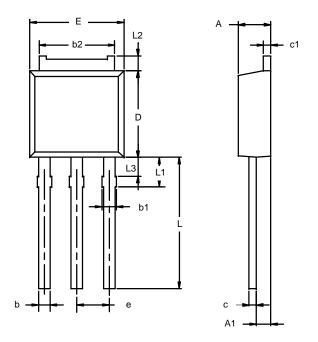


* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel



TO-251AA



Note: Dimensio	n L3 is for r	eference only.
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	MILLIMETERS		INC	HES
Dim	Min	Max	Min	Max
Α	2.21	2.38	0.087	0.094
A1	0.89	1.14	0.035	0.045
b	0.71	0.89	0.028	0.035
b1	0.76	1.14	0.030	0.045
b2	5.23	5.43	0.206	0.214
С	0.46	0.58	0.018	0.023
с1	0.46	0.58	0.018	0.023
D	5.97	6.22	0.235	0.245
Е	6.48	6.73	0.255	0.265
е	2.28	2.28 BSC		BSC
L	3.89	9.53	0.153	0.375
L1	1.91	2.28	0.075	0.090
L2	0.89	1.27	0.035	0.050
L3	1.15	1.52	0.045	0.060



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